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I hereby certify that this paper (along with any paper referred to as being attached of enclosed) is being deposited with the U.S. Postal Service on the date shown below with sufficient postage as First Class Mail, in an envelope addressed to: Attention: Certificate of Correction Branch, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Style V. While

Docket No.: 108298515US2

(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Letters Patent of:

Lee et al.

Patent No.: 7,094,131

Issued: August 22, 2006

For: MICROELECTRONIC SUBSTRATE

HAVING CONDUCTIVE MATERIAL WITH BLUNT CORNERED APERTURES, AND ASSOCIATED METHODS FOR REMOVING

CONDUCTIVE MATERIAL

REQUEST FOR CERTIFICATE OF CORRECTION PURSUANT TO 37 CFR 1.322

Attention: Certificate of Correction Branch

Commissioner for Patents

P.O. Box 1450

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Sir:

Certificate

NOV 2 9 2006

Of Cor

Upon reviewing the above-identified patent, Patentee noted a typographical error which should be corrected.

In the References Cited, Other Publications, Page 3, please include the following reference that was cited in an Information Disclosure Statement filed on November 24, 2003, and initialed by the Examiner on August 10, 2005:

JUCHNIEWICZ, R. et al. "Influence of Pulsed Current on Platinised Titanium and Tantalum Anode Durability," International Congress on Metallic Corrosion, Proceedings - Volume 3, pp. 449-453, Toronto, June 3-7, 1984.

Patent No.: 7,094,131 Docket No.: 108298515US2

The error was not in the application as filed by applicant; accordingly no fee is required.

Transmitted herewith is a proposed Certificate of Correction effecting such amendment. Patentee respectfully solicits the granting of the requested Certificate of Correction.

Applicant believes no fee is due with this request. However, if a fee is due, please charge our Deposit Account No. 50-0665, under Order No. 108298515US2 from which the undersigned is authorized to draw.

Dated: _/// &&/06

Respectfully submitted

Chen Llang

Registration No.: 51,945

PERKINS COIE LLP

P.O. Box 1247

Seattle, Washington 98111-1247

(206) 359-8000

(206) 359-7198 (Fax)

Attorney for Applicant

PTO/SB/44 (04-05)

Approved for use through 04/30/2007. OMB 0651-0033

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UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

Page _1_ of _1_

PATENT NO.

7,094,131

APPLICATION NO. :

. 09/887,767

ISSUE DATE

August 22, 2006

INVENTOR(S)

Lee et al.

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

References Cited, Other Publications, Page 3:

JUCHNIEWICZ, R. et al. "Influence of Pulsed Current on Platinised Titanium and Tantalum Anode Durability," International Congress on Metallic Corrosion, Proceedings -Volume 3, pp. 449-453, Toronto, June 3-7, 1984.